Applic. No.: 09/923,701

## Amendments to the Claims



Claims 1-9 (withdrawn).

Claim 10 (currently amended): A method for removing an organic material from a semiconductor device, which comprises the steps:

providing a reactor;

inserting at least one semiconductor device with having at least one deposited organic layer of photoresist material into the reactor;

inserting fluid ingredients for removing the <del>organic</del> photoresist material from the semiconductor device into a heated fluid;

transmitting an emitted optical radiation towards the fluid; receiving transmitted optical radiation transmitted through the fluid;

detecting an optical radiation intensity not influenced by process induced bubbles; and

controlling the insertion of at least one of the ingredients in dependence on the detected optical radiation intensity.

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Claim 11 (original): The method according to claim 10, which further comprises the steps of modulating the emitted optical radiation and demodulating the transmitted optical radiation.

Claim 12 (original): The method according to claims 10, which further comprises the step of detecting maximum values of the optical radiation intensity.

Claim 13 (original): The method according to claim 10, which further comprises the step of inserting sulphuric acid and hydrogen peroxide into the fluid.

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Claim 14 (original): The method according to claim 13, which further comprises the step of controlling the insertion of hydrogen peroxide.

Claim 15 (original): The method according to claim 10, which further comprises the step of monitoring the optical radiation intensity over a defined time period.

Claim 16 (original): The method according to claim 10, wherein the step of transmitting an emitted optical radiation towards the fluid is carried out by transmitting a blue light towards the fluid.

Claim 17 (original): The method according to claim 10, which further comprises the step of comparing the detected optical radiation intensity with an initial radiation intensity detected before the semiconductor device is inserted into the reactor.

Claim 18 (original): The method according to claim 10, which further comprises the steps of comparing a detected value of the optical radiation intensity with values of a pre-defined table on defined time stamps, and controlling the amount of one of the fluid ingredients to be inserted into the fluid in dependence on the comparison.

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Claim 19 (original): The method according to claims 10, which further comprises the step of detecting a minimum value of a measured optical radiation intensity curve.

Claim 20 (cancelled).

Claim 21 (withdrawn).